

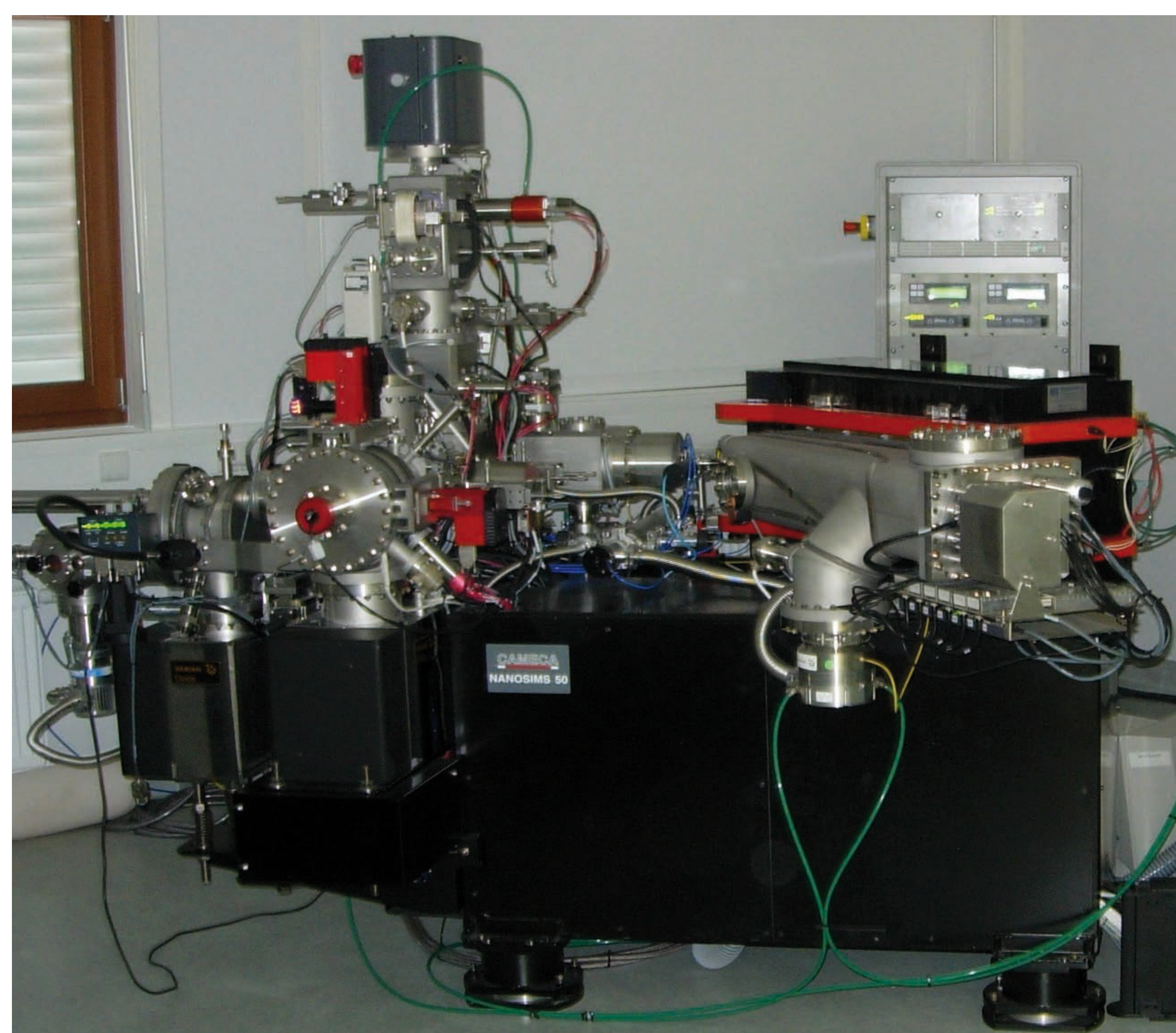
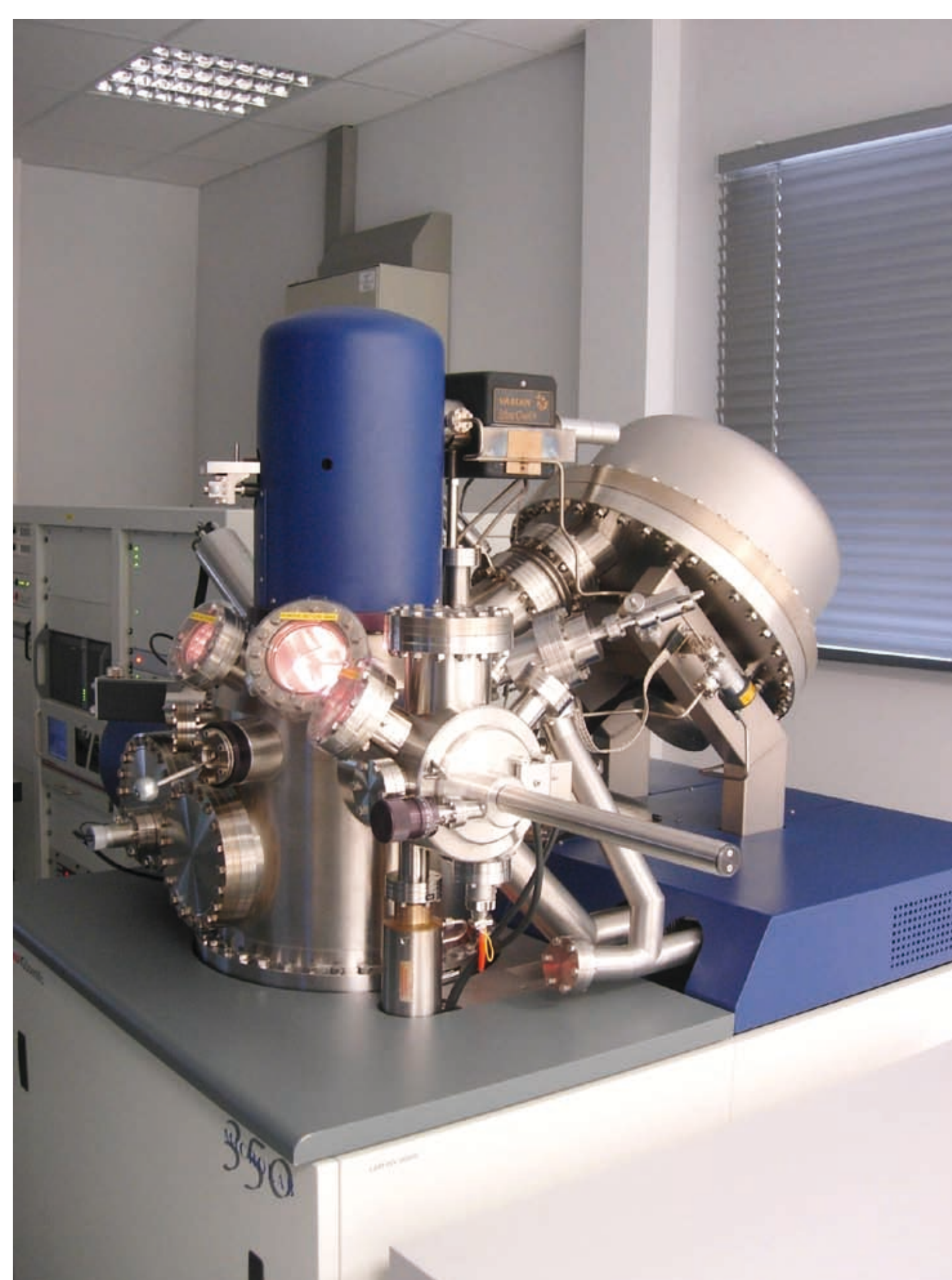
European PhD School on

“NANOANALYSIS USING FINELY FOCUSED ION AND ELECTRON BEAMS”

BELVAUX, Luxembourg
March 13th – 17th 2006

“SECONDARY ION MASS SPECTROMETRY (SIMS),
TRANSMISSION ELECTRON MICROSCOPY (TEM),
AUGER ELECTRON SPECTROSCOPY (AES):
A COMPREHENSIVE OVERVIEW”

- > Ion and electron - matter interactions
- > Instrumentation
- > Applications



The PhD School organized by the NANOBEAMS NoE focuses on SIMS, TEM and AES.
It consists of four different weeks composing a two year cycle:

- > The first week provides an overview of the three techniques
- > The three other weeks aim at forming specialists in the field

Each week proposes theoretical tutorials and practical sessions.

REGISTRATION

No registration fees

Application deadline: 27th February 2006

Audience: scientists with a degree in physics, biology and material science
30 attendees maximum

Teaching program and Application: www.nanobeams.org

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